

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10590768	JENSEN ET AL.
	Examiner	Art Unit
	Young J Kim	1637

SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES

Search Notes	Date	Examiner
Patent Databases (USPT, USPPG, EPO, JP0, DERWENT, IBM-TDB) - see enclosed for text search strategy	8/6/2009	/YJK/

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

	/Young J Kim/ Primary Examiner. Art Unit 1637
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